

L Number	Hits	Search Text	DB	Time stamp
1	1	("5895264").PN.	USPAT; US-PGPUB	2003/10/20 11:10
2	0	korean with patent with "941273"	JPO;	2003/10/20
3	0	korean with patent with "94-1273"	DERWENT JPO;	11:11 2003/10/20
4	0	"1994" and hyundai and (kim adj jae adj gap)	DERWENT JPO;	11:12 2003/10/20
5	0	"1994" and hyundai and (kim with jae with gap)	DERWENT JPO;	11:14 2003/10/20
6	0	"1994" and (hyundai adj electronics) and (kim with jae with gap)	DERWENT JPO;	11:14 2003/10/20
7	0	"1994" and hyundai and (kim adj jae adj gap)	DERWENT JPO;	11:15 2003/10/20
8	0	"1994" and (hyundai adj electronics) and (kim with jae with gap)	USPAT; US-PGPUB	2003/10/20 11:15
9	0	(hyundai adj electronics) and (kim with jae with gap)	USPAT	2003/10/20 11:15
10	0	(hyundai adj electronics) and (kim with jae with gap)	US-PGPUB	2003/10/20 11:15
11	2748	438/637, 640, 672, 675.cc1s.	USPAT; US-PGPUB	2003/10/20 11:47
12	1649	438/637, 640, 672, 675.cc1s. and @ad<19990916	USPAT; US-PGPUB	2003/10/20 11:48
13	5045	438/618, 253, 586, 595, 639, 672.cc1s.	USPAT; US-PGPUB	2003/10/20 11:48
14	3072	438/618, 253, 586, 595, 639, 672.cc1s. and @ad<19990916	USPAT; US-PGPUB	2003/10/20 11:48
15	2299	(438/618, 253, 586, 595, 639, 672.cc1s. and @ad<19990916) not (438/637, 640, 672, 675.cc1s. and @ad<19990916)	USPAT; US-PGPUB	2003/10/20 12:44
16	16396	(samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))	USPAT; US-PGPUB	2003/10/20 13:02
17	1011	((samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))) and (contact adj hole))	USPAT; US-PGPUB	2003/10/20 13:02
18	343	((samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))) and (contact adj hole)) and opening	USPAT; US-PGPUB	2003/10/20 13:03
19	148	(((samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))) and (contact adj hole)) and opening) and @ad<19990916	USPAT; US-PGPUB	2003/10/20 12:58
20	113600	(samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))	EPO; JPO; DERWENT	2003/10/20 13:02
21	1187	((samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))) and (contact adj hole))	EPO; JPO; DERWENT	2003/10/20 13:03
22	80	((samsung or (kim with in with sung) or (park with joon with soo) or (lee with jung with hyeong) or (kang with hyun with jae))) and (contact adj hole)) and opening	EPO; JPO; DERWENT	2003/10/20 13:03

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1 Influence of short circuits on data of contact and via open circuits determined by a novel weave test structure
Hess, C.; Weiland, L.H.;
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Kitagawa, H.; Maeda, T.; Murata, S.; Maki, T.; Kaeriyama, T.; Hyslop, A.; Nishimura, A.;
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3 New materials and new analysis method for high-efficiency a-Si solar cells
Nakano, S.; Nakamura, N.; Ninomiya, K.; Tarui, H.; Matsuyama, T.; Nishikuni, M.; Kiyama, S.; Hishikawa, Y.; Dohjo, H.; Tsuda, S.; Ohnishi, M.; Kishi, Y.; Kuwano, Y.;
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Kim, J.C.; Schwartz, R.J.; Gray, J.L.;
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[\[Abstract\]](#) [\[PDF Full-Text \(220 KB\)\]](#) **IEEE CNF****5 Silicon concentrator solar cells using mass-produced, flat-plate cell fabrication technology**

King, R.R.; Mitchell, K.W.; Walle, J.R.; Aldrich, D.L.; Gee, J.M.; O'Neill, M.; Kammer, N.; McEntee, J.; Stark, P.;
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[\[Abstract\]](#) [\[PDF Full-Text \(452 KB\)\]](#) **IEEE CNF****6 Si nanoprocess for vertical double-gate MOSFET fabrication**

Masahara, M.; Matsukawa, T.; Ishii, K.; Yongxun Liu; Sakamoto, K.; Kanemaru, S.; Suzuki, E.;
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[\[Abstract\]](#) [\[PDF Full-Text \(272 KB\)\]](#) **IEEE CNF****7 Direct tunneling at the front contact of amorphous silicon p-i-n devices**

Rubinelli, F.A.;
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Gleskova, H.; Konenkamp, R.; Wagner, S.; Chen, D.S.;
Electron Device Letters, IEEE , Volume: 17 Issue: 6 , June 1996

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[\[Abstract\]](#) [\[PDF Full-Text \(400 KB\)\]](#) **IEEE JNL****9 Influence of short circuits in data contact and via open circuits determined by a novel weave test structure***Hess, C.; Weiland, L.H.;*

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[\[Abstract\]](#) [\[PDF Full-Text \(1532 KB\)\]](#) **IEEE JNL****10 Modeling of dry development in bilayer-resist process for 140-nm contact hole patterning***Sung Bo Hwang; Kim, W.D.; Edgar, T.F.;*

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[\[Abstract\]](#) [\[PDF Full-Text \(310 KB\)\]](#) **IEEE JNL****11 Longevity of optically activated, high gain GaAs photoconductive semiconductor switches***Loubriel, G.M.; Zutavern, F.J.; Mar, A.; Hjalmarson, H.P.; Baca, A.G.;**O'Malley, M.W.; Helgeson, W.D.; Falk, R.A.; Brown, D.J.;*

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[\[Abstract\]](#) [\[PDF Full-Text \(560 KB\)\]](#) **IEEE CNF****13 A highly reliable multilevel interconnection process for 0.6 μm CMOS devices***Takata, Y.; Ishii, A.; Matsuura, M.; Ohsaki, A.; Iwasaki, M.; Miyazaki, J.; Fujiwara, N.; Komori, J.; Katayama, T.; Nakao, S.; Kotani, H.;* VLSI Multilevel Interconnection Conference, 1991, Proceedings., Eighth International IEEE, 11-12 June 1991

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